


<b>Search Notes</b>  	<b>Application/Control No.</b>  10535160	<b>Applicant(s)/Patent Under Reexamination</b>  NEWKIRK ET AL.
	<b>Examiner</b>  Anthony Weier	<b>Art Unit</b>  1794

SEARCHED			
Class	Subclass	Date	Examiner
426	629, 455, 459, 463, 469, 578, 634, 656	3/29/10	AW
100	112, 110, 117, 126, 145	3/29/10	AW

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor search	3/29/10	AW

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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